

# **Device Modeling Report**

COMPONENTS: THYRISTOR  
PART NUMBER: BT151X-800  
MANUFACTURER: PHILIPS SEMICONDUCTOR



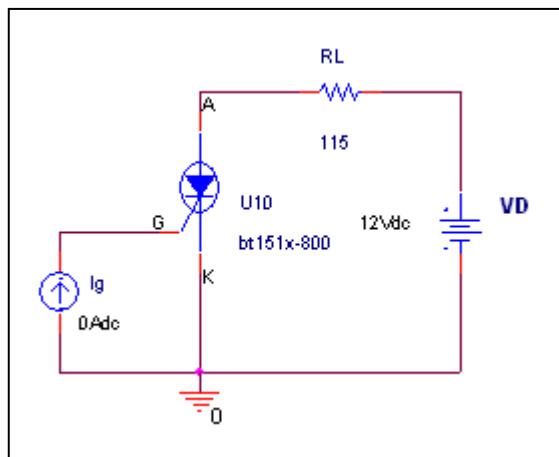
**Bee Technologies Inc.**

## DIODE MODEL

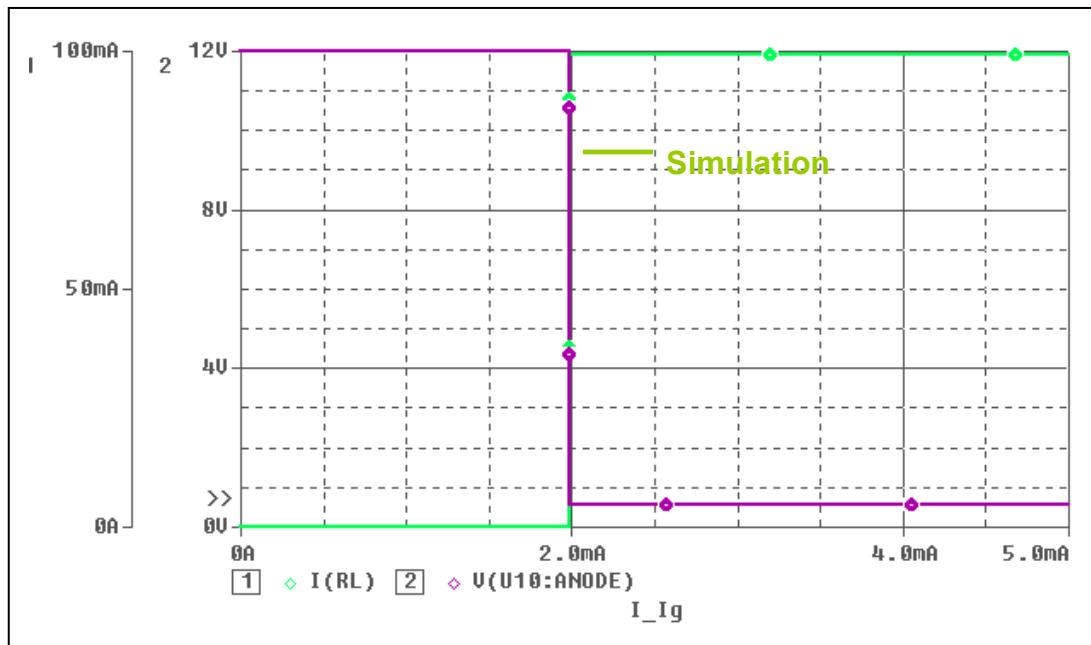
Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## IG-VT Characteristic

Evaluation Circuit



Simulation result

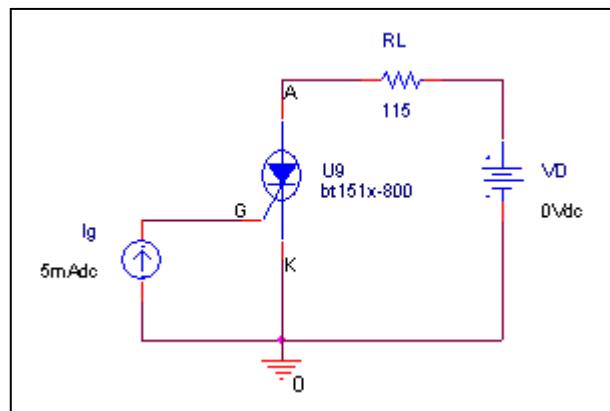


Comparison Table

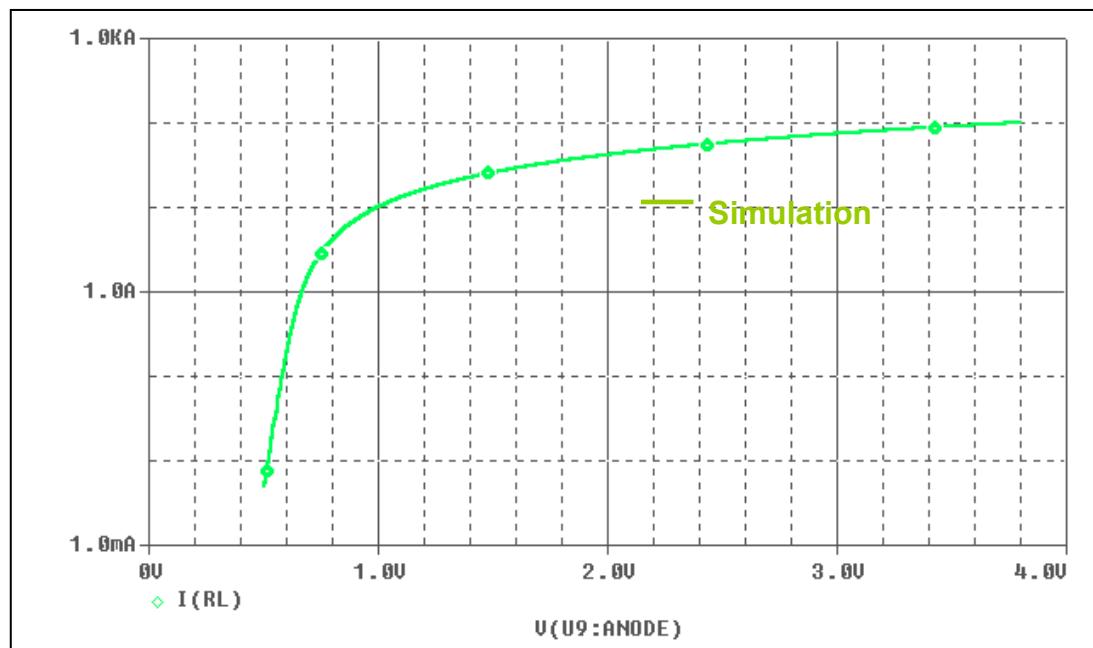
	Measurement	Simulation	% Error
I <sub>G<sub>T</sub></sub> (mA)	2	1.9821	-0.89500
V <sub>G<sub>T</sub></sub> (V)	0.6	0.582525	-2.91250

## ITM-VTM Characteristic

Evaluation Circuit



Simulation result

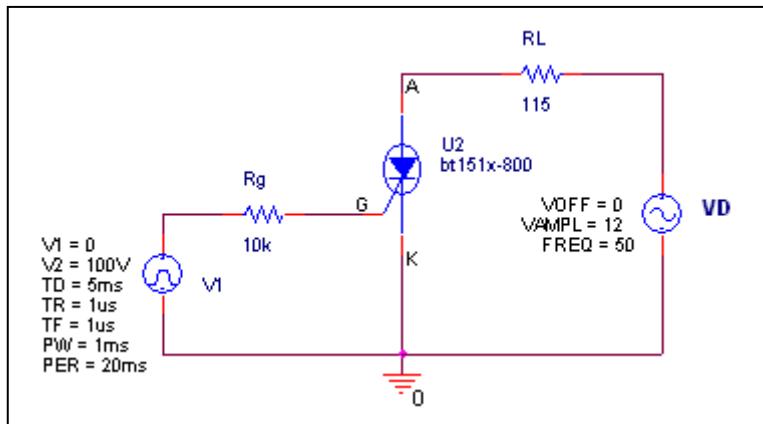


Comparison Table

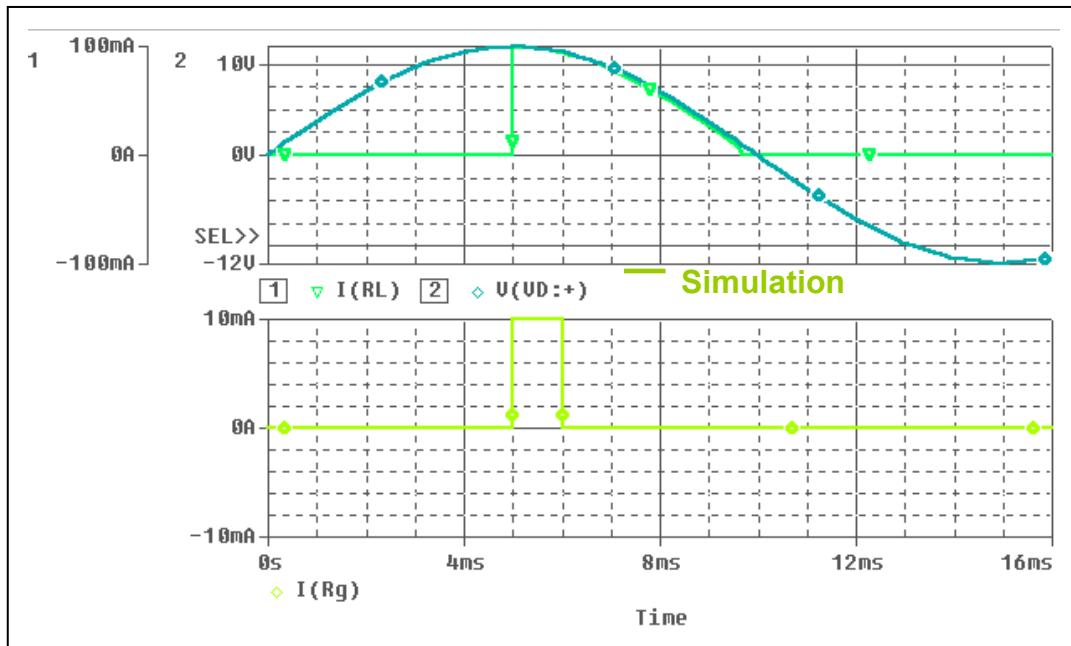
At ITM=23A	Measurement	Simulation	% Error
VTM(V)	1.4	1.4214	1.52857

## Holding Characteristic (IH)

Evaluation Circuit



Simulation result

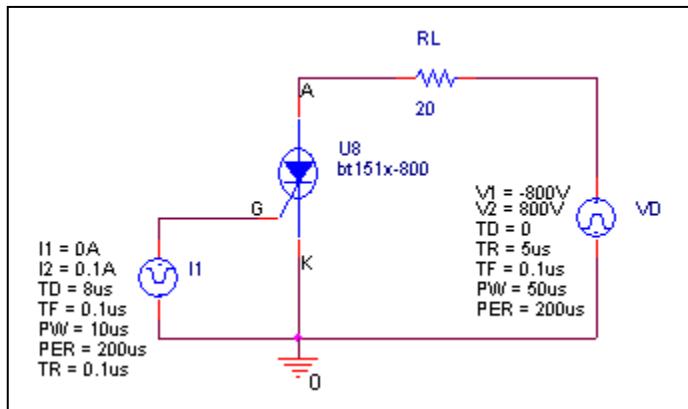


Comparison Table

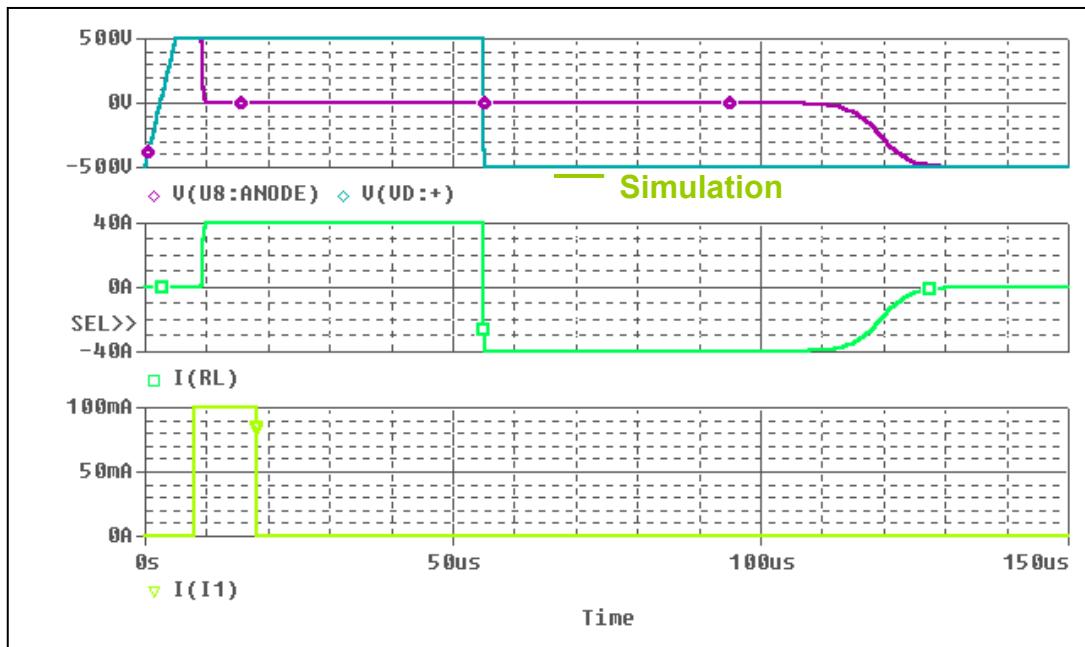
$VD=12V$	Measurement	Simulation	% Error
$IH(mA)$	7	6.8495	-2.15000

## Switching Time Characteristic

Evaluation Circuit



Simulation result



Comparison Table

	Measurement	Simulation	%Error
Ton(us)	2	2.0369	1.84500
Toff(us)	70	70.913	1.30429